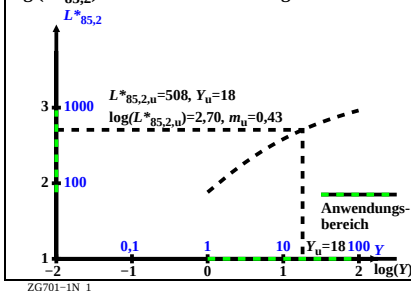
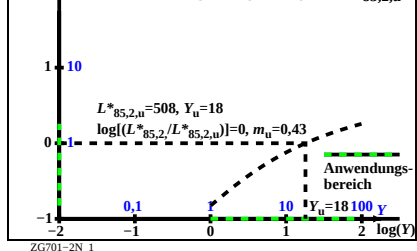


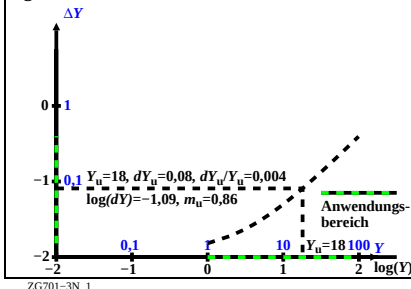
$\log(L^*_{85,2})$ LABJND Musterhelligkeit



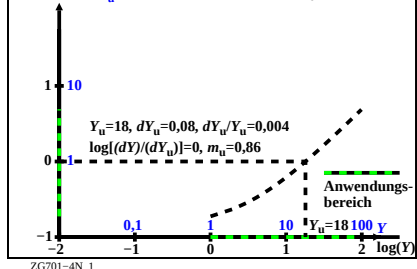
$\log(L^*_{85,2}/L^*_{85,2,u})$ LABJND Musterhelligkeit $L^*_{85,2}$ normiert für die Umgebungshelligkeit $L^*_{85,2,u}$



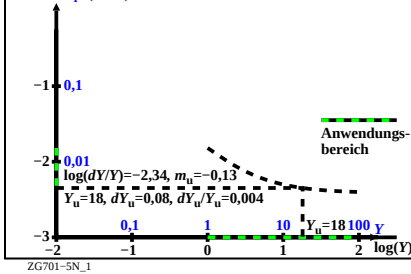
$\log(\Delta Y)$ CIE-Normfarbwertdifferenz ΔY



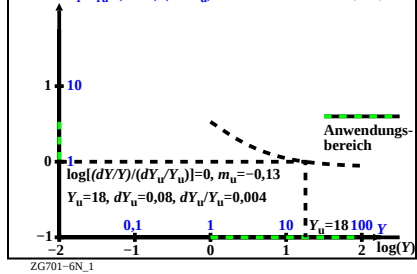
$\log(\Delta Y/\Delta Y_u)$ CIE-Normfarbwertdifferenz ΔY normiert für ΔY_u



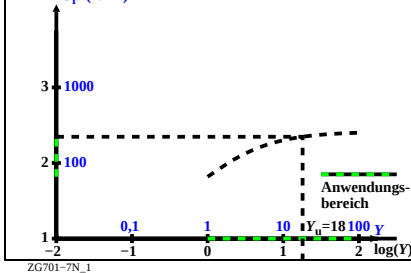
$\log(\Delta Y/Y)$ CIE Y-basierter Kontrast $C_r=(\Delta Y/Y)$



$\log[(\Delta Y/Y) / (\Delta Y_u/Y_u)]$ CIE Y-Kontrast $C_r/C_{ru}=(\Delta Y/Y)/(\Delta Y_u/Y_u)$ normiert für $\Delta Y_u/Y_u$



$\log(Y/\Delta Y)$ CIE Y-basierte Empfindlichkeit $S_r=(Y/\Delta Y)$



$\log[(Y/\Delta Y) / (Y_u/\Delta Y_u)]$ CIE Y-Empfindlichkeit $S_r/S_{ru}=(Y/\Delta Y)/(Y_u/\Delta Y_u)$ normiert für $Y_u/\Delta Y_u$

